

Notice of References Cited	Application/Control No. 10/772,311		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner EDMUND H. LEE		Art Unit 1732	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0178514	09-2004	Lee et al.	257/787
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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